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## Boron-doped superlattices and Bragg reflectors in diamond NIMS <sup>1</sup>, Grenoble Alpes Univ. <sup>2</sup>, CNRS – Inst. NEEL <sup>3</sup>, CEA – INAC <sup>4</sup>, CNRS – GEMaC and

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**Introduction** The diamond delta-doping contributed to our growth expertise of metallic diamond boron-doped layers ( $p^+ > 5 \ 10^{20} \ \text{at.cm}^{-3}$ ) and nominally undoped ( $p^- < 5 \ 10^{17} \ \text{at.cm}^{-3}$ ) by Microwave Plasma-assisted CVD (MPCVD) [1]. The film thickness and doping control of such layers were based on the difference of their refractive indexes by spectroscopic ellipsometry [2]. In this study, the periodic variation of these refractive indexes arranged in a multilayer stack will be used to build Bragg reflectors (BR). Further, the BR wavelength will be finely tuned to the emission of NV or SiV color centers.

**Experiment** Homoepitaxial diamond films so-called superlattices (SL) were obtained by

periodically overgrowing  $p^+$  with  $p^-$  layers on diamond (100)-oriented substrates without turning off the plasma. Optical spectra were monitored in real time during MPCVD diamond growth to improve the BR efficiency. SL periods and the abruptness of  $p^+/p^-$  interfaces were confirmed by X-ray diffraction (XRD) experiments.

**Results** Fig. 1 displays a transmittance dip in the 550–750 nm range of a  $p^+/p^-$  diamond SL composed of 20 periods. This bore proof that the periodicity and interfaces abruptness of the  $p^+/p^-$  stack had a sufficient quality to confer BR properties. Thicknesses measured by ellipsometry were ~17 nm and ~118 nm for  $p^+$  and  $p^-$  layers, respectively. Fig. 2 shows the corresponding XRD curve of the (004) reflection measured in a high resolution diffractometer. The substrate (S) and five orders of satellite peaks ( $\pm 1... \pm 5$ ) are revealed. The simulation of these satellites peaks provided a  $p^+/p^-$  period of ~133 nm, in good agreement with the ellipsometry fit. 42 20 periods p\*/p<sup>\*</sup> stack 38 600 650 700 750 Wavelength (nm)

Figure 1 A 3% transmittance dip through a boron-doped superlattice grown on a Ib-type diamond substrate.



**Figure 2** Experimental (004) XRD intensity curve for a 20  $p^+/p^-$  periods superlattice structure, whose period were ~133 nm. S and (±1... ±5) indicate the position of substrate peak and the order of satellites peaks, respectively.

[1] A. Fiori et al, Appl. Phys. Express 6, 045801 (2013).

<sup>[2]</sup> J. Bousquet et al, Appl. Phys. Lett. 104, 021905 (2014).